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<u>L23</u>	L22 and (gini near index\$3)	1	<u>L23</u>
<u>L22</u>	L21 and L19	4	<u>L22</u>
<u>L21</u>	707/5-7.ccls.	3136	<u>L21</u>
<u>L20</u>	L19 and (gini near index\$3)	1	<u>L20</u>
<u>L19</u>	leaf\$1 same node\$2 same (distance\$2 or range\$2) same neighbor\$3	32	<u>L19</u>
<u>L18</u>	L17 and (gini near index\$3)	1	<u>L18</u>
<u>L17</u>	L16 and L1	9	<u>L17</u>
<u>L16</u>	707/\$.ccls.	23117	<u>L16</u>
<u>L15</u>	L13 and (near\$3 near neighbor\$3)	0	<u>L15</u>
<u>L14</u>	L13 and (nearest near neighbor)	0	<u>L14</u>
<u>L13</u>	L4 and (leaf\$1 same node\$2 same range\$2)	2	<u>L13</u>
<u>L12</u>	L11 and (leaf\$2 adj node\$2)	8	<u>L12</u>
<u>L11</u>	L10 and range\$2	10	<u>L11</u>
<u>L10</u>	L9 and distance\$2	15	<u>L10</u>

<u>L9</u>	L4 and (leaf\$1 same node\$2)	32	<u>L9</u>
<u>L8</u>	L4 and (leaf\$1 same node\$2 same distance\$2)	1	<u>L8</u>
<u>L7</u>	L6 not L5	0	<u>L7</u>
<u>L6</u>	L1 and L3	1	<u>L6</u>
<u>L5</u>	L1 and L4	1	<u>L5</u>
<u>L4</u>	"gini index"	54	<u>L4</u>
<u>L3</u>	gini near index\$3	52	<u>L3</u>
<u>L2</u>	L1 and (gini near index\$3)	1	<u>L2</u>
<u>L1</u>	leaf\$1 same node\$2 same distance\$2 same neighbor\$3	28	<u>L1</u>

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<u>L19</u>	leaf\$1 same node\$2 same (distance\$2 or range\$2) same neighbor\$3	32	<u>L19</u>
<u>L18</u>	L17 and (gini near index\$3)	1	<u>L18</u>
<u>L17</u>	L16 and L1	9	<u>L17</u>
<u>L16</u>	707/\$.ccls.	23117	<u>L16</u>
<u>L15</u>	L13 and (near\$3 near neighbor\$3)	0	<u>L15</u>
<u>L14</u>	L13 and (nearest near neighbor)	0	<u>L14</u>
<u>L13</u>	L4 and (leaf\$1 same node\$2 same range\$2)	2	<u>L13</u>
<u>L12</u>	L11 and (leaf\$2 adj node\$2)	8	<u>L12</u>
<u>L11</u>	L10 and range\$2	10	<u>L11</u>
<u>L10</u>	L9 and distance\$2	15	<u>L10</u>
<u>L9</u>	L4 and (leaf\$1 same node\$2)	32	<u>L9</u>
<u>L8</u>	L4 and (leaf\$1 same node\$2 same distance\$2)	1	<u>L8</u>
<u>L7</u>	L6 not L5	0	<u>L7</u>

<u>L6</u>	L1 and L3	1	<u>L6</u>
<u>L5</u>	L1 and L4	1	<u>L5</u>
<u>L4</u>	"gini index"	54	<u>L4</u>
<u>L3</u>	gini near index\$3	52	<u>L3</u>
<u>L2</u>	L1 and (gini near index\$3)	1	<u>L2</u>
<u>L1</u>	leaf\$1 same node\$2 same distance\$2 same neighbor\$3	28	<u>L1</u>

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
L13 and (near\$3 near neighbor\$3)	0

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result set

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<u>L15</u>	L13 and (near\$3 near neighbor\$3)	0	<u>L15</u>
<u>L14</u>	L13 and (nearest near neighbor)	0	<u>L14</u>
<u>L13</u>	L4 and (leaf\$1 same node\$2 same range\$2)	2	<u>L13</u>
<u>L12</u>	L11 and (leaf\$2 adj node\$2)	8	<u>L12</u>
<u>L11</u>	L10 and range\$2	10	<u>L11</u>
<u>L10</u>	L9 and distance\$2	15	<u>L10</u>
<u>L9</u>	L4 and (leaf\$1 same node\$2)	32	<u>L9</u>
<u>L8</u>	L4 and (leaf\$1 same node\$2 same distance\$2)	1	<u>L8</u>
<u>L7</u>	L6 not L5	0	<u>L7</u>
<u>L6</u>	L1 and L3	1	<u>L6</u>
<u>L5</u>	L1 and L4	1	<u>L5</u>
<u>L4</u>	"gini index"	54	<u>L4</u>
<u>L3</u>	gini near index\$3	52	<u>L3</u>
<u>L2</u>	L1 and (gini near index\$3)	1	<u>L2</u>

L1 leaf\$1 same node\$2 same distance\$2 same neighbor\$3

28 L1

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
L17 and (gini near index\$3)	1

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<u>L18</u>	L17 and (gini near index\$3)	1	<u>L18</u>
<u>L17</u>	L16 and L1	9	<u>L17</u>
<u>L16</u>	707/\$.ccls.	23117	<u>L16</u>
<u>L15</u>	L13 and (near\$3 near neighbor\$3)	0	<u>L15</u>
<u>L14</u>	L13 and (nearest near neighbor)	0	<u>L14</u>
<u>L13</u>	L4 and (leaf\$1 same node\$2 same range\$2)	2	<u>L13</u>
<u>L12</u>	L11 and (leaf\$2 adj node\$2)	8	<u>L12</u>
<u>L11</u>	L10 and range\$2	10	<u>L11</u>
<u>L10</u>	L9 and distance\$2	15	<u>L10</u>
<u>L9</u>	L4 and (leaf\$1 same node\$2)	32	<u>L9</u>
<u>L8</u>	L4 and (leaf\$1 same node\$2 same distance\$2)	1	<u>L8</u>
<u>L7</u>	L6 not L5	0	<u>L7</u>
<u>L6</u>	L1 and L3	1	<u>L6</u>
<u>L5</u>	L1 and L4	1	<u>L5</u>

<u>L4</u>	"gini index"	54	<u>L4</u>
<u>L3</u>	gini near index\$3	52	<u>L3</u>
<u>L2</u>	L1 and (gini near index\$3)	1	<u>L2</u>
<u>L1</u>	leaf\$1 same node\$2 same distance\$2 same neighbor\$3	28	<u>L1</u>

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File: PGPB

Mar 27, 2003

PGPUB-DOCUMENT-NUMBER: 20030061213

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20030061213 A1

TITLE: Method for building space-splitting decision tree

PUBLICATION-DATE: March 27, 2003

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Yu, Philip Shi-Lung	Chappaqua	NY	US	
Wang, Haixun	Tarrytown	NY	US	

US-CL-CURRENT: 707/7

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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PGPUB-DOCUMENT-NUMBER: 20030061213

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20030061213 A1

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☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Scalable classifiers with dynamic pruning***Gupta, S.K.; Somayajulu, D.V.L.N.; Arora, J.K.; Vasudha, B.;*

Database and Expert Systems Applications, 1998. Proceedings. Ninth International Workshop on , 26-28 Aug. 1998

Pages: 246 - 251

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☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Optimal partitioning for classification and regression trees**

Chou, P.A.;

Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 13 , Issue: 4 , April 1991
Pages:340 - 354[\[Abstract\]](#)[\[PDF Full-Text \(1308 KB\)\]](#)**IEEE JNL**

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